Opto Edu A63.7088 Schottky Field Emission Gun Scanning Electron Microscope SE+CCD 1x~2000000x

Basic Information

- Place of Origin:
- Brand Name:
- Certification:
- Model Number:
- Minimum Order Quantity:
- Price:
- · Packaging Details:
- Delivery Time:
- Payment Terms:
- Supply Ability:





Product Specification

- Resolution:
- Magnification:
- Electron Gun:
- Voltage:
- Electron Beam:
- Vacuum System:
- Highlight:

1.0nm@30KV(SE),	1.5nm@1KV(SE)

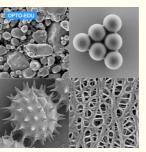
- 1x~2000000x
- Schottky Field Emission Gun
- Accelerating Voltage 0.02~30KV
- 1pA~20nA
 - 1 Sputter Ion Pump, 1 Turbo Molecular Pump, 1 Mechanical Pump
 - SE+CCD Scanning Electron Microscope, 1x~2000000x Scanning Electron Microscope, opto edu microscope



More Images







Our Product Introduction

Schottky Field Emission Gun Scanning Electron Microscope, SE+CCD, 1x~2000000x

1x~200000x With Detector SEx2+BSE+CCD, Extention Port For EDS, EBSD, CL
 Schottky Field Emission Gun Voltage 0.02 30kV, Resolution 1nm@15KV(SE), 1.5nm@1KV(SE)
 5 Axes Auto Stage X=125, Y=125, Z=50, R=360°, T=-5°~+70° Specimen Room Ф330xH260mm
 Vaccum Pumps: 1 Ion +1 Turbo Molecular+ 1 Mechanical, Including Computer, Windows & Software, Control Panel
 Composite Lens With Electrostatic Lens + Magnetic Lens Worry Free Imaging of Magnetic Samples



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A63.7088

Schottky Field Emission Gun Scanning Electron Microscope, SE+CCD, 1x~2000000x



A63.7088 Introduction

OPTO-EDU

The A63.7088 scanning electron microscope uses thermal field emission electron gun (Schottky FEG) technology. The electron optical tube incorporates advanced full-tube acceleration technology to ensure excellent imaging performance of the electron beam under low acceleration voltage and is suitable for various materials (Especially for high-resolution imaging of samples that are non-conductive and not resistant to electron irradiation). A63.7088 is equipped with two secondary electron detectors inside the mirror (on the optical axis) and in the sample chamber (Everhart-Thornley), a backscattered electron detector, a scanning transmission electron detector, etc., which can efficiently collect the emitted electrons excited from the sample. Imaging a variety of electronic signals can reveal the microscopic morphology and structural information of the sample to the greatest extent.



A63.7088		
Resolution	1.0nm@30KV(SE), 1.5nm@1KV(SE)	
Magnification	1x~200000x	
Electron Gun	Schottky Field Emission Gun	
Voltage	Accelerating Voltage 0.02~30KV	
Electron Beam	1pA~20nA	
Vacuum System	1 Sputter Ion Pump, 1 Turbo Molecular Pump, 1 Mechanical Pump	
Detector	SE in Lens, SE in Sample Room, BSE, CCD	
Extend Port	Extend Ports On Sample Room For BSE, EDS, EBSD, CL etc.	
Specimen Stage	5 Axes Auto Stage, Travel Range: X=125mm, Y=125mm, Z=50mm, R=360°, T=-5°~+70°	
Max Specimen	Specimen Room Dia.330mm, Height 260mm	
Image System	Real Still Image Max Resolution 256x256~16k~16k Pixels	
Computer & Software	PC Work Station Windows System, With Professional Image Analysis Software To Fully Control Whole SEM Microscope Operation, Mouse, Keyboard	
Control Panel	Included	
Dimension & Weight	Main Body 1900x1100x1800mm, Total Weight 800Kg	
Optional Accessories		
A50.7091	Ion Beam Cleaner	
A50.7092	Field Emission Gun Lamp	

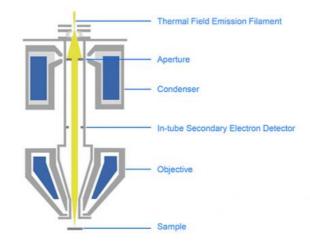
A63.7088 Features



Superior Electron-optics Design

• Thermal field emission electron gun, stable beam, high imaging resolution

Full tube acceleration technology ensures high imaging performance of electron beam at low acceleration voltage
Composite lens design of electrostatic lens and magnetic lens, the objective lens has no magnetic leakage, and the imaging of magnetic samples is worry-free



► Comprehensive Signal Collection System

• Can simultaneously collect signals from two types of secondary electrons, backscattered electrons and transmitted electrons.

• The sample morphology and composition contrast are displayed simultaneously to reveal the sample's microscopic morphology and composition information to the greatest extent.



